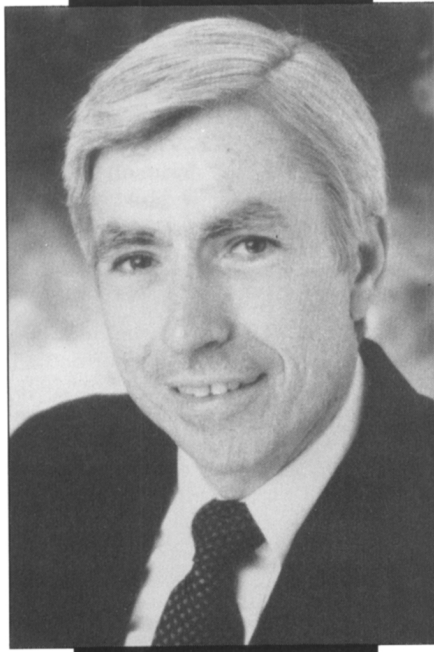


MRS Celebrates 20th Anniversary

During 1993, the Materials Research Society celebrates its 20th anniversary. In 1973, we emerged as a new society emphasizing an interdisciplinary approach to materials research. MRS members energetically organized high-quality meetings and brought a fresh and enthusiastic approach to everything they did. As a result, we can be quite proud of what we have accomplished at this comparatively young age as a professional society. Indeed, MRS is widely respected, and its methods are now being emulated by many of our sister societies.

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When I first realized that the MRS's second decade would be completed during my term as president, I determined that we should not miss this opportunity to look back on our origins. By taking time to celebrate, we could not only be proud of our past, we could also reflect on those principles that have served us well. At the same time, this opportunity



A handwritten signature in black ink, which appears to read "Tom Picraux".

would help educate our newer members about that history and to record it in first-hand reports while the principal players were still available.

Thus, over the past nine months, we have been running articles in the *Bulletin* by former MRS presidents summarizing their perspectives and recollections on the Society. With this issue, we complete the publication of these pieces for every one of our former presidents.

To round out this retrospective part of our 20th year celebration, we include in this issue a short history of MRS in two parts (see pages 73–83). The first part may be viewed as a description of our nucleation phase, and the second part as a description of our growth phase. In the former, one of our principal founders, Rustum Roy, recounts the beginnings of MRS, including its conception, gestation, birth, and infancy. In the second, I present a summary of the more recent events, including the rapid developments of the 1980s on up to the present time.

I hope all members will take a moment to look at this thumbnail sketch of our history. Taken together with the presidents' articles, it gives us perspective on a very exciting two decades. After all, how can you really appreciate where you're going if you don't know where you've been.

Tom Picraux
1993 MRS President

U.S. RESEARCH

The Materials Research Society and
Synergistic Technologies, Inc.
are cataloguing key researchers in
U.S. academia and national laboratories.

Look for further details in the
October issue of the *MRS Bulletin*.

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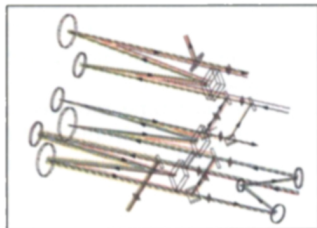


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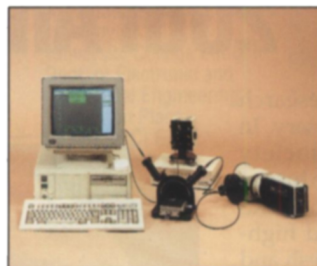
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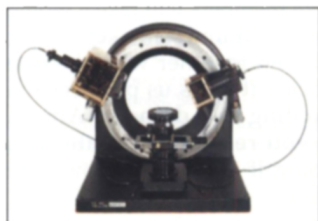
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